

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/552,507	INOUE ET AL.	
Examiner	Art Unit	
LOIS ZHENG	1793	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED				
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SEARCH NO (INCLUDING SEARC)
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Inventorship search	2/10/2010	LLZ
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